TECHNOMETRICS
CONTENTS OF VOLUME 44
Numbers 173–176

Articles 1, 99, 205, 305
Book Reviews 80, 185, 286, 396
Editorial Collaborators 412

Index to Volume 44 413
Articles, by Author 413
Books Reviewed, by Author 414
Book Reviewers 417

INDEX TO VOLUME 44 (2002)

ARTICLES, BY AUTHOR

Ankenman, Bruce E., Liu, Hui, Karr, Alan F., and Picka, Jeffrey D., "A Class of Experimental Designs for Estimating a Response Surface and Variance Components," 45

Beattie, Scott D., Fong, Duncan K. H., and Lin, Dennis K. J., "A Two-Stage Bayesian Model Selection Strategy for Supersaturated Designs," 55

Bi, Zhuoxin (*see* Lee, Herbert K. H.)

Blower, Paul E. (*see* Fligner, Michael A.)

Brown, P. J. (*see* Öjelund, H.)

Chen, Argon, and Elsayed, E. A., "Design and Performance Analysis of the Exponentially Weighted Moving Average Mean Estimate for Processes Subject to Random Step Changes," 379

Cheng, Shao-Wei, and Wu, C. F. J., "Choice of Optimal Blocking Schemes in Two-Level and Three-Level Designs," 269

Christensen, William F., and Sain, Stephan R., "Accounting for Dependence in a Flexible Multivariate Receptor Model," 328

Cornell, John A. (*see* Kowalski, Scott M.)

Dean, A. M. (*see* Prescott, P.)

Del Castillo, Enrique, "Closed-Loop Disturbance Identification and Controller Tuning for Discrete Manufacturing Processes," 134

Deng, Lih-Yuan, and Tang, Boxin, "Design Selection and Classification for Hadamard Matrices Using Generalizated Minimum Aberration Criteria," 173

Draper, Norman R., and Pukelsheim, Friedrich, "Generalized Ridge Analysis Under Linear Restrictions, With Particular Applications to Mixture Experiments Problems," 250 (*see* Prescott, P.)

Dudewicz, Edward J. (*see* Nelson, Peter R.)

Elsayed, E. A. (*see* Chen, Argon)

Ferreira, Marco A. R. (*see* Lee, Herbert, K. H.)

Fligner, Michael A., Verducci, Joseph S., and Blower, Paul E., "A Modification of the Jaccard-Tanimoto Similarity Index for Diverse Selection of Chemical Compounds Using Binary Strings," 110

Fong, Duncan K. H. (*see* Beattie, Scott D.)

Golowich, Steven, Landwehr, James, and Scott, Vander Wiel, "Interplay Between Physics and Statistics for Modeling Optical Fiber Bandwidth," 215

Hicks, Ruel D. (*see* Piepel, Greg F.)

Higdon, Dave M. (*see* Lee, Herbert K. H.)

Hinich, Melvin J. (*see* Li, Ta-Hsin)

Huwang, Longcheen, Wu, C. F. J., and Yen, C. H., "The Idle Column Method: Design Construction, Properties and Comparisons," 347

Iyer, Hari, and Mathew, Thomas, "Comments on Chiang (2001)," 284

Jiang, Wei, Wu, Huaiqing, Tsung, Fugee, Nair, Vijayan N., and Tsui, Kwok-Leung, "Proportional Integral Derivative Charts for Process Monitoring," 205

Jones, Allison L. (*see* Sullivan, Joe H.)

Joseph, Roshan V., and Wu, Jeff C. F., "Robust Parameter Design of Multiple-Target Systems," 338

Kabaila, Paul, and Lloyd, Chris J., "The Importance of the Designated Statistic on Buehler Upper Limits on a System Failure Probability," 390

Karr, Alan F. (*see* Ankenman, Bruce E.)

Kowalski, Scott M., Cornell, John A., and Vining, Geoffrey G., "Split-Plot Designs and Estimation Methods for Mixture Experiments With Process Variables," 72

Lam, Raymond L. H., Welch, William J., and Young, Stanley S., "Uniform Coverage Designs for Molecule Selection," 99

Landwehr, James (*see* Golowich, Steven)

Lee, Herbert K. H., Higdon, Dave M., Bi, Zhuoxin, Ferreira, Marco A. R., and West, Mike, "Markov Random Field Models for High-Dimensional Parameters in Simulations of Fluid Flow in Porous Media," 230

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TECHNOMETRICS, NOVEMBER 2002, VOL. 44, NO. 4
DOI 10.1198/004017002188618617

Lewis, S. M. (*see* Prescott, P.)
Li, Huo, and Mee, Robert W., "Better Foldover Fractions for Resolution III 2^{k-p} Designs," 278
Li, Ta-Hsin, and Hinich, Melvin J., "A Filter Bank Approach for Modeling and Forecasting Seasonal Patterns," 1
Lin, Dennis K. J. (*see* Beattie, Scott D.)
Liu, Hui (*see* Ankenman, Bruce E.)
Lloyd, Chris J. (*see* Kabaila, Paul)
Loeppky, Jason L. (*see* Piepel, Greg F.)
Madsen, H. (*see* Öjelund, H.)
Maronna, Ricardo A., and Zamar, Ruben H., "Robust Estimates of Location and Dispersion for High-Dimensional Datasets," 307
Mathew, Thomas (*see* Iyer, Hari)
Mee, Robert W. (*see* Li, Huo)
Meeker, William Q. (*see* Nordman, Daniel J.; Wu, Huaiqing)
Nair, Vijayan N. (*see* Jiang, Wei)
Nelson, Peter R., and Dudewicz, Edward J., "Exact Analysis of Means With Unequal Variances," 152
Nordman, Daniel J., and Meeker, William Q., "Weibull Prediction Intervals for a Future Number of Failures," 15
Notz, William, Editors Report, 305
Öjelund, H., Brown, P. J., Madsen, H., and Thyregod, P., "Prediction Based on Mean Subset," 369
Olive, David J., "Applications of Robust Distances for Regression," 64
Picka, Jeffrey D. (*see* Ankenman, Bruce E.)
Piepel, Greg F., Hicks, Ruel D., Szychowski, Jeff M., and Loeppky, Jason L., "Methods for Assessing Curvature and Interaction in Mixture Experiments," 161
Prescott, P., Dean, A. M., Draper, N. R., and Lewis, S. M., "Mixture Experiments: ILL-Conditioning and Quadratic Model Specification," 260
Pukelsheim, Friedrich (*see* Draper, Norman R.)
Raftery, Adrian E. (*see* Walsh, Daniel C. I.)
Reichert, Peter, Schervish, Mark, and Small, Mitchell J., "An Efficient Sampling Technique for Bayesian Inference With Computationally Demanding Models," 318
Sain, Stephan R. (*see* Christensen, William F.)
Schervish, Mark (*see* Reichert, Peter)
Simonoff, Jeffrey S., and Tsai, Chih-Ling, "Score Tests for the Single Index Model," 142
Small, Mitchell J. (*see* Reichert, Peter)
Sullivan, Joe H., and Jones, Allison L., "A Self-Starting Control Chart for Multivariate Individual Observations," 24
Szychowski, Jeff M. (*see* Piepel, Greg F.)
Tang, Boxin (*see* Deng, Lih-Yuan)
Thyregod, P. (*see* Öjelund, H.)
Tsai, Chih-Ling (*see* Simonoff, Jeffrey S.)
Tsui, Kwok-Leung (*see* Jiang, Wei)
Tsung, Fugee (*see* Jiang, Wei)
Vander Wiel, Scott (*see* Golowich, Steven)
Vangel, Mark G., "Lot Acceptance and Compliance Testing Using the Sample Mean and an Extremum," 242
Verducci, Joseph S. (*see* Fligner, Michael A.)
Vining, Geoffrey G. (*see* Kowalski, Scott M.)
Walsh, Daniel C. I., and Raftery, Adrian E., "Detecting Mines in Minefields With Linear Characteristics," 34
Welch, William J. (*see* Lam, Raymond L. H.)
West, Mike (*see* Lee, Herbert K. H.)
Wu, C. F. J. (*see* Cheng, Shao-Wei; Huwang, Longcheen)
Wu, Huaiqing, and Meeker, William Q., "Early Detection of Reliability Problems Using Information From Warranty Databases," 120 (*also see* Jiang, Wei)
Wu, Jeff C. F. (*see* Joseph, Roshan V.)
Xu, Hongquan, "An Algorithm for Constructing Orthogonal and Nearly-Orthogonal Arrays With Mixed Levels and Small Runs," 356
Yen, C. H. (*see* Huwang, Longcheen)
Young, Stanley S. (*see* Lam, Raymond L. H.)
Zamar, Ruben H. (*see* Maronna, Ricardo A.)

BOOKS REVIEWED, BY AUTHOR

Abbott, James C., *Running Your Machines with SPC*, 90; *SPC: Practical Understanding of Capability by Implementing Statistical Process Control, Third Edition*, 187
Albert, James H., and Rossman, Allan J., *Workshop Statistics: Discovery With Data, A Bayesian Approach*, 293
Albert, Jim, and Bennett, Jay, *Curve Ball*, 96
Arthur, Jay, *Six Sigma Simplified: Quantum Improvement Made Easy*, 189
ASQ Chemical and Process Industries Division Chemical Interest Committee, *Trusting Measurement Results in the Chemical and Process Industries*, 93
Atkinson, Anthony, and Riani, Marco, *Robust Diagnostic Regression Analysis*, 81
Balakrishnan, N., and Koutras, Markos V., *Runs and Scans With Applications*, 399
Bean, Michael A., *Probability: The Science of Uncertainty*, 294
Bedford, Tim, and Cooke, Roger, *Probabilistic Risk Analysis*, 402
Benichou, Jacques (*see* Gail, Mitchell H.)
Bennett, Jay (*see* Albert, Jim)
Berger, Roger L. (*see* Casella, George)
Berry, Kenneth J. (*see* Mielke, Paul W., Jr.)
Bethlehem, Jelke G., and van der Heijdenk, Peter G. M., *COMPSTAT: Proceeding in Computational Statistics, 2000*, 96
Bhote, Keki R., *The Ultimate Six Sigma*, 410
Booker, Jane M. (*see* Meyer, Mary A.)
Boyadjieva, Lidia N. (*see* Vuchkov, Ivan N.)
Braatz, R. (*see* Chiang, L.)
Caponetto, R. (*see* Fortuna, L.)
Carmona, René, Hwang, Wen-Liang, and Torrésani, Bruno, *Practical Time-Frequency Analysis: Gabor and Wavelet Transforms With an Implementation in S*, 196
Casella, George, and Berger, Roger L., *Statistical Inference (2nd ed.)*, 407
Cavanagh, Roland R. (*see* Pande, Peter S.)
Chan, Ngai, *Time Series*, 408

Chandra, Jeya M., *Statistical Quality Control*, 397
Chatfield, Chris, *Time-Series Forecasting*, 194
Chen, Ming-Hui (*see* Ibrahim, Joseph G.)
Cheng, Runwei (*see* Gen, Mitsuo)
Chiang, L., Russell, E., and Braatz, R., *Fault Detection and Diagnosis in Industrial Systems*, 197
Christensen, Ronald, *Advanced Linear Modeling, Second Edition*, 198
Clemen, Robert T., and Reilly, Terence, *Making Hard Decisions, Second Edition*, 199
Coles, Stuart, *An Introduction to Statistical Modeling of Extreme Values*, 397
Colton, Theodore (*see* Redmond, Carol)
Condra, Lloyd W., *Reliability Improvement with Design of Experiments*, 93
Congdon, Peter, *Bayesian Statistical Modelling*, 291
Cooke, Roger (*see* Bedford, Tim)
Cornell, John, *Experiments With Mixtures, Third Edition*, 299
Cox, D. R. (*see* Titterington, D. M.)
Crowder, Martin, *Classical Competing Risks*, 298
Crowe, Dana, and Feinberg, Alec (editors), *Design for Reliability*, 401
Debnath, Lokenath (editor), *Wavelet Transforms and Time-Frequency Signal Analysis*, 87
Der, Geoff, and Everitt, Brian S., *A Handbook of Statistical Analyses Using SAS, Second Edition*, 300
Derr, Janice, *Statistical Consulting*, 89
Devore, Jay (*see* Peck, Roxy)
Devore, Jay, and Peck, Roxy, *Statistics: The Exploration and Analysis of Data, Fourth Edition*, 297
Diamond, William J., *Practical Experiment Designs (3rd ed.)*, 400
Dielman, Terry E., *Applied Regression Analysis for Business and Economics, Third Edition*, 192
Dillman, Don A. (*see* Groves, Robert M.)
Dobson, Annette J., *An Introduction to Generalized Linear Models (2nd ed.)*, 406
Dräger, Klaus (*see* von Collani, Elart)
Duda, Richard O., Hart, Peter E., and Stork, David G., *Pattern Classification, Second Edition*, 87
Dudewicz, Edward J. (*see* Karian, Zaven A.)
Dugard, Pat (*see* Todman, John B.)
Dunn, Graham (*see* Everitt, Brian S.)
Eckes, George, *The Six Sigma Revolution*, 199
Edwards, David, *Introduction to Graphical Modelling, Second Edition*, 197
El-Shaarawi, Abdel H., and Piegorsch, Walter W. (editors), *Encyclopedia of Environmetrics Vols. 1–4*, 408
Elston, Robert, Olson, Jane, and Palmer, Lyle (editors), *Biostatistical Genetics and Genetic Epidemiology*, 409
Eltinge, John L. (*see* Groves, Robert M.)
Erjavec, John (*see* Lawson, John)
Everitt, Brian S. (*see* Der, Geoff)
Everitt, Brian S., *A Handbook of Statistical Analyses Using S-PLUS, Second Edition*, 300
Everitt, Brian S., and Dunn, Graham, *Applied Multivariate Data Analysis (2nd ed.)*, 407
Everitt, B. S., and Rabe-Hesketh, Sophia, *Analyzing Medical Data Using S-PLUS*, 201
Ewens, Warren J., and Grant, Gregory R., *Statistical Methods in Bioinformatics*, 96
Fahrmeir, Ludwig, and Tutz, Gerhard, *Multivariate Statistical Modelling Based on Generalized Linear Models*, 94
Feinberg, Alec (*see* Crowe, Dana)
Finkelstein, Michael O., and Levin, Bruce, *Statistics for Lawyers, Second Edition*, 200
Fitzgerald, W. J., Smith, R. L., Walden, A. T., and Young, P. C. (editors), *Nonlinear and Nonstationary Signal Processing*, 88
Fortuna, L., Rizzotto, G., Lavorgna, M., Nunnari, G., Xibilia, M. G., and Caponetto, R., *Soft Computing*, 199
Gail, Mitchell H., and Benichou, Jacques, *Encyclopedia of Epidemiologic Methods*, 202
Gen, Mitsuo, and Cheng, Runwei, *Genetic Algorithms and Engineering Optimization*, 95
Glaz, Joseph, Naus, Joseph, and Wallenstein, Sylvan, *Scan Statistics*, 198
Goldstein, H. (*see* Leyland, A. H.)
Golyandina, Nina E., Nekrutkin, Vladimir V., and Zhigljavsky, Anantoly A., *Analysis of Time Series Structure SSA and Related Techniques*, 290
Good, Phillip I., *Applying Statistics in the Courtroom*, 200; *Resampling Methods, Second Edition*, 299
Govindarajulu, Z., *Elements of Sampling Theory and Methods*, 191
Grambsch, Patricia M. (*see* Therneau, Terry M.)
Grant, Gregory R. (*see* Ewens, Warren J.)
Groves, Robert M., Dillman, Don A., Eltinge, John L., and Little, Roderick J. A. (editors), *Survey Nonresponse*, 301
Hart, Peter E. (*see* Duda, Richard O.)
Haykin, Simon (*see* Yee, Paul V.)
Heckard, Robert F. (*see* Utts, Jessica M.)
Hoehn, E. (*see* Stauffer, F.)
Hoerl, Roger, and Snee, Ronald, *Statistical Thinking*, 92
Hosmer, David W., and Lemeshow, Stanley, *Applied Logistic Regression*, 81
Hougaard, Philip, *Analysis of Multivariate Survival Data*, 86
Houlding, Simon W., *Practical Geostatistics*, 83
Hubele, Norma F. (*see* Montgomery, Douglas C.)
Hwang, Wen-Liang (*see* Carmona, René)
Ibrahim, Joseph G., Chen, Ming-Hui, and Sinha Debajyoti, *Bayesian Survival Analysis*, 201
Janacek, Gareth, *Practical Time Series*, 195
Johnson, Dallas E. (*see* Milliken, George A.)
Karian, Zaven A., and Dudewicz, Edward J., *Fitting Statistical Distributions: The Generalized Lambda Distribution and Generalized Bootstrap Methods*, 194
Kinzelbach, W. (*see* Stauffer, F.)
Kirby, Michael, *Geometric Data Analysis: An Empirical Approach to Dimensionality Reduction and the Study of Patterns*, 196
Kolvar, K. (*see* Stauffer, F.)
Koutras, Markos V. (*see* Balakrishnan, N.)
Krause, Andreas (*see* Millard, Steven)
Lachin, John M., *Biostatistical Methods: The Assessment of Relative Risks*, 95
Lavorgna, M. (*see* Fortuna, L.)
Lamprecht, James L., *Interpreting ISO 9000:2000 With Statistical Methodology*, 406

Lawson, John, and Erjavec, John, *Modern Statistics for Engineering and Quality Improvement*, 186
Lemeshow, Stanley (*see* Hosmer, David W.)
Lenz, H.-J., and Wilrich, P.-T. (editors), *Frontiers in Statistical Quality Control 6*, 302
Levin, Bruce (*see* Finkelstein, Michael O.)
Leyland, A. H., and Goldstein, H. (editors), *Multilevel Modelling of Health Statistics*, 410
Little, Roderick J. A. (*see* Groves, Robert M.)
Liu, Jun S., *Monte Carlo Strategies in Scientific Computing*, 403
Manly, Bryan F. J., *Statistics for Environmental Science and Management*, 201
Marchette, David J., *Computer Intrusion Detection and Network Monitoring*, 294
Martens, Harald, and Martens, Magni, *Multivariate Analysis of Quality: An Introduction*, 186
Martens, Magni (*see* Martens, Harald)
Martinez, Angel R. (*see* Martinez, Wendy L.)
Martinez, Wendy L., and Martinez, Angel R., *Computational Statistics Handbook With MATLAB®*, 405
McLachlan, Geoffrey, and Peel, David, *Finite Mixture Models*, 82
McPherson, Glen, *Applying and Interpreting Statistics: A Comprehensive Guide, Second Edition*, 296
Meyer, Mary A., and Booker, Jane M., *Eliciting and Analyzing Expert Judgment: A Practical Guide*, 193
Mielke, Paul W., Jr., and Berry, Kenneth J., *Permutation Methods: A Distance Function Approach*, 289
Millard, Steven, and Krause, Andreas, *Applied Statistics in the Pharmaceutical Industry*, 410
Milliken, George A., and Johnson, Dallas E., *Analysis of Messy Data, Volume III: Analysis of Covariance*, 288
Monahan, John F., *Numerical Methods of Statistics*, 91
Montgomery, Douglas C. (*see* Myers, Raymond H.)
Montgomery, Douglas C., Peck, Elizabeth A., and Vining, Geoffrey G., *Introduction to Linear Regression Analysis, Third Edition*, 191
Montgomery, Douglas C., and Runger, George C., *Applied Statistics and Probability for Engineers*, 93
Montgomery, Douglas C., Runger, George C., and Hubele, Norma F., *Engineering Statistics, Second Edition*, 197
Morgan, Byron J. T., *Applied Stochastic Modelling*, 91
Mücklich, Frank (*see* Ohser, Joachin)
Müller, Peter, and Vidakovic, Brian (editors), *Bayesian Inference in Wavelet-Based Models*, 87
Müller, Werner G., *Collecting Spatial Data: Optimum Design of Experiments for Random Fields, Second Revised Edition*, 296
Myers, Raymond H., and Montgomery, Douglas C., *Response Surface Methodology, Second Edition*, 298
Myers, Raymond H., Montgomery, Douglas C., and Vining, Geoffrey G., *Generalized Linear Models*, 287
Naus, Joseph (*see* Glaz, Joseph)
Nekrutkin, Vladimir V. (*see* Golyandina, Nina E.)
Neuman, Robert P. (*see* Pande, Peter S.)
Newman, Stephen C., *Biostatistical Methods in Epidemiology*, 301
Nunnari G. (*see* Fortuna, L.)
Ohser, Joachin, and Mücklich, Frank, *Statistical Analysis of Microstructures in Materials Science*, 86
Olsen, Chris (*see* Peck, Roxy)
Palmer, Lyle (*see* Elston, Robert)
Pande, Peter S., Neuman, Robert P., and Cavanagh, Roland R., *The Six Sigma Way*, 299
Parmigiani, Giovanni, *Modeling in Medical Decision Making*, 409
Pawitan, Yudi, *In All Likelihood: Statistical Modeling and Inference Using Likelihood*, 404
Peck, Elizabeth A. (*see* Montgomery, Douglas C.)
Peck, Roxy (*see* Devore, Jay)
Peck, Roxy, Olsen, Chris, and Devore, Jay, *Introduction to Statistics and Data Analysis*, 90
Peel, David (*see* McLachlan, Geoffrey)
Pesarin, Fortunato, *Multivariate Permutation Tests*, 290
Piegorsch, Walter W. (*see* El-Shaarawi, Abdel H.)
Press, James S., and Tanur, Judith M., *The Subjectivity of Scientists and the Bayesian Approach*, 292
Rabe-Hesketh, Sophia (*see* Everitt, B. S.)
Raftery, Adrian E., Tanner, Martin A., and Wells, Martin T. (editors), *Statistics in the 21st Century*, 302
Rao, Poduri S. R. S., *Sampling Methodologies With Applications*, 398; *Variance Components Estimation*, 82
Redmond, Carol, and Colton Theodore (editors), *Biostatistics in Clinical Trials*, 202
Reilly, Terence (*see* Clemen, Robert T.)
Reiss, R.-D., and Thomas, M., *Statistical Analysis of Extreme Values, Second Edition*, 295
Riani, Marco (*see* Atkinson, Anthony)
Rizzotto, G. (*see* Fortuna, L.)
Rosenblatt, Judah, *Basic Statistical Methods and Models for the Sciences*, 401
Rossman, Allan J. (*see* Albert, James H.)
Roy, Ranjit K., *Design of Experiments Using the Taguchi Approach: 16 Steps to Product and Process Improvement*, 289
Rud, Olivia Parr, *Data Mining Cookbook*, 94
Runger, George C. (*see* Montgomery, Douglas C.)
Russell, E. (*see* Chiang, L.)
Schinazi, Rinaldo B., *Probability With Statistical Applications*, 402
Sinha, Debajyoti (*see* Ibrahim, Joseph G.)
Skiena, Steven, *Calculated Bets*, 404
Smith, Gerald M., *Statistical Process Control and Quality Improvement, Fourth Edition*, 188
Smith, Patricia L., *A Primer for Sampling Solids, Liquids, and Gases*, 190
Smith, Peter J., *Analysis of Failure and Survival Data*, 397
Smith, R. L. (*see* Fitzgerald, W. J.)
Snee, Ronald (*see* Hoerl, Roger)
Stamatis, D. H., *Six Sigma and Beyond: Foundations of Excellent Performance*, 300; *Six Sigma and Beyond: Problem Solving and Basic Mathematics*, 300
Stauffer, F., Kinzelbach, W., Kolvar, K., and Hoehn, E. (editors), *Calibration and Reliability in Groundwater Modelling*, 84
Stephens, Kenneth S., *The Handbook of Applied Acceptance Sampling*, 90

Stork, David G. (*see* Duda, Richard O.)
Tanner, Martin A. (*see* Raftery, Adrian E.)
Tanur, Judith M. (*see* Press, James S.)
Therneau, Terry M., and Grambsch, Patricia M., *Modeling Survival Data*, 85
Thomas, M. (*see* Reiss, R.-D.)
Thompson, Steven K., *Sampling (2nd ed.)*, 407
Titterington, D. M., and Cox, D. R., *Biometrika: One Hundred Years*, 302
Todman, John B., and Dugard, Pat, *Single-Case and Small-n Experimental Designs*, 401
Torrésani, Bruno (*see* Carmona, René)
Tranter, Roy L. (editor), *Design and Analysis in Chemical Research*, 190
Tsay, Ruey, *Analysis of Financial Time Series*, 408
Tufte, Edward R., *The Visual Display of Quantitative Information (2nd ed.)*, 400
Tutz, Gerhard (*see* Fahrmeir, Ludwig)
Utts, Jessica M., and Heckard, Robert F., *Mind on Statistics*, 405
van der Heijdenk, Peter, G. M. (*see* Bethlehem, Jelke G.)
Vidakovic, Brian (*see* Müller, Peter)
Vining, Geoffrey G. (*see* Montgomery, Douglas C.); (*see* Myers, Raymond H.)
von Collani, Elart, and Dräger, Klaus, *Binomial Distribution Handbook for Scientists and Engineers*, 290
Vose, David, *Risk Analysis, Second Edition*, 95
Vuchkov, Ivan N., and Boyadjieva, Lidia N., *Quality Improvement With Design of Experiments*, 188
Walden, A. T. (*see* Fitzgerald, W. J.)
Wallenstein, Sylvan (*see* Glaz, Joseph)
Wells, Martin T. (*see* Raftery, Adrian E.)
Wilcox, Rand R., *Fundamentals of Modern Statistical Methods*, 83
Wilrich, P.-T. (*see* Lenz, H.-J.)
Xibilia, M. G. (*see* Fortuna, L.)
Yee, Paul V., and Haykin, Simon, *Regularized Radial Basis Function Networks: Theory and Applications*, 294
Young, P. C. (*see* Fitzgerald, W. J.)
Zhigljavsky, Anantoly A. (*see* Golyandina, Nina E.)

BOOK REVIEWERS

Alexander, Melvin, 189
Altland, Henry W., 192
Anderson-Cook, Christine M., 89
Babu, Gutti J., 83
Babu, Jogesh G., 290
Barker, Lawrence E., 87
Basu, Asit, 402
Bayne, Charles K., 186
Bodt, Barry A., 186, 294
Borkowf, Craig B., 194
Breneman, James E., 294
Burdick, Richard K., 288
Campbell, Katherine, 295
Chan, Victor, 404
Chatfield, Chris, 87
Chernick, Michael R., 82, 399
Coburn, Timothy C., 83
Conklin, Joseph D., 81, 298
Dobrow, Robert, 91
Finkelstein, Dianne, 397
Ganocy, Stephen J., 291
Gatliffe, Thomas R., 84
Ghosh, Subir, 191
Goodman, Jay H., 296
Gray, Brian J., 191
Greenwood, Mark C. (*see* Huzurbazar, Snehalata V.)
Gruber, Marvin H. J., 292
Hembree, Barry, 90
Hesterberg, Tim, 403
Heydorn, Richard P., 401
Huzurbazar, Snehalata V., and Greenwood, Mark C., 293
Iyer, Hari, 296
Jensen, Donald R., 290
Kenyon, James R., 86
Kerkering, Charles J., 193
Kushler, Robert H., 405
Lin, Haiqun, and Zelterman, Daniel, 85
Lin, Yachen, 196
Liu, Shin Ta, 289
Mazu, Michael J., 398
McCormack, D. W., Jr., 401
McGuire, Stephen A., 406
Minton, Paul D., 297
Mitra, Amit, 397
Mulrow, Edward J., 400
Nash, Maliha S., 196
Nemeth, Margaret A., 190
Placzkowski, Gene, 90
Portier, Kenneth, 81
Qian, Lianfen, 294
Qiu, Peihua, 86
Robinson, Timothy, 188
Rukhin, Andrew L., 290
Rutherford, Jim, 400
Sarkar, Pradipta, 195
Sauter, Roger M., 90, 404
Scargle, Jeffrey D., 88
Seaver, Willian L., 405
Sengupta, Sailes K., 87
Shanmugam, Ramalingam, 82
Smith, Eric P., 397
Taam, Winson, 402
Van Bowen, Jacob, Jr., 401
Van Nostrand, Richard Craig, 289
Wassell, James T., 91
Wehrly, Thomas E., 194
Wills, Graham J., 197
Yates, Phillip, 187
Zelterman, Daniel (*see* Lin, Haiqun)
Ziegel, Eric R., 287
Zimmer, Lora, 188